

Dkt. 01196

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

BINH VU THIEN et al

PCT

Serial No.: 09/926,489

Filed: November 13, 2001

For: METHOD AND DEVICE FOR EXTRACTION OF ELECTRODES IN A
VACUUM AND EMISSION CATHODES FOR SUCH DEVICE



INFORMATION DISCLOSURE STATEMENT

Honorable Commissioner of Patents and Trademarks
Washington, D.C. 20231

Sir:

Submitted herewith are copies of the references
cited in the International Search Report which are listed on
the attached Form PTO-1449.

Respectfully submitted,

Ira J. Schultz
Registration No. 28666

Form PTO-1449 INFORMATION DISCLOSURE CITATION IN AN APPLICATION (Use several sheets if necessary)				ATTY DOCKET NO. 01196		APPLICATION NO. 09/926,489							
				APPLICANT Binh VU THIEN et al									
				FILING DATE November 13, 2001		GROUP							
U.S. PATENT DOCUMENTS													
EXAMINER INITIAL	DOCUMENT NUMBER						DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE		
	3	0	9	8	1	6	8	3/59	Aigrain				
	3	1	1	4	0	7	0	12/58	Stratton				
	3	1	2	1	8	0	9	2/64	Atalla				
	3	9	1	6	2	2	7	10/75	Mize				
	5	2	6	6	8	6	7	11/30	Sakurai				
	5	3	5	9	2	5	7	10/94	Bunch et al				
FOREIGN PATENT DOCUMENTS													
	DOCUMENT NUMBER						DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION		
	0	6	9	6	0	4	3	2/96	EP			YES	NO
		9	6	4	7	6	0	8/50	FR				
	1	2	2	5	6	7	5	7/60	FR				
	05	3	4	2	9	8	3	12/93	JP Abstract				
	08	0	0	7	7	4	6	1/96	JP Abstract				
	98	0	6	1	3	5		2/98	WO				
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)													
	~	XP-002126517 "Ballistic Electron Emission Microscopy Study of Schottky Contacts on 6H- and 4H-SiC", Im et al, Applied Physics Letters, Vol. 72, No. 7, 1998, pp. 839-841.											
	•	XP-004081165 "Electron emission Characteristics of Metal/Diamond Field Emitters", Sugino et al, Elsevier Science S.A., Vol. 6, No. 5-7, pp. 889-892.											
	•	XP-000749210 "Theory and Experimental Results of a New Diamond Surface-Emission Cathode", Geis et al, The Lincoln Laboratory Journal, Vol. 10, No. 1, pp. 3-18.											
EXAMINER								DATE CONSIDERED					
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.													